

520/530/580.495  
Microfabrication Laboratory  
and  
520.773  
Advanced Topics in  
Fabrication and Microengineering

# Wet Etching

Reading for this lecture:

- (1) May, Chapter 5.1
- (2) Madou p163-p177 (website)
- (3) Williams paper (website)

HW #5: Due Oct. 14

# Etch Parameters

- Etch Rate:

- rate of material removal ( $\mu\text{m}/\text{min}$ )
- function of concentration, agitation, temperature, density and porosity of the thin film or substrate,...

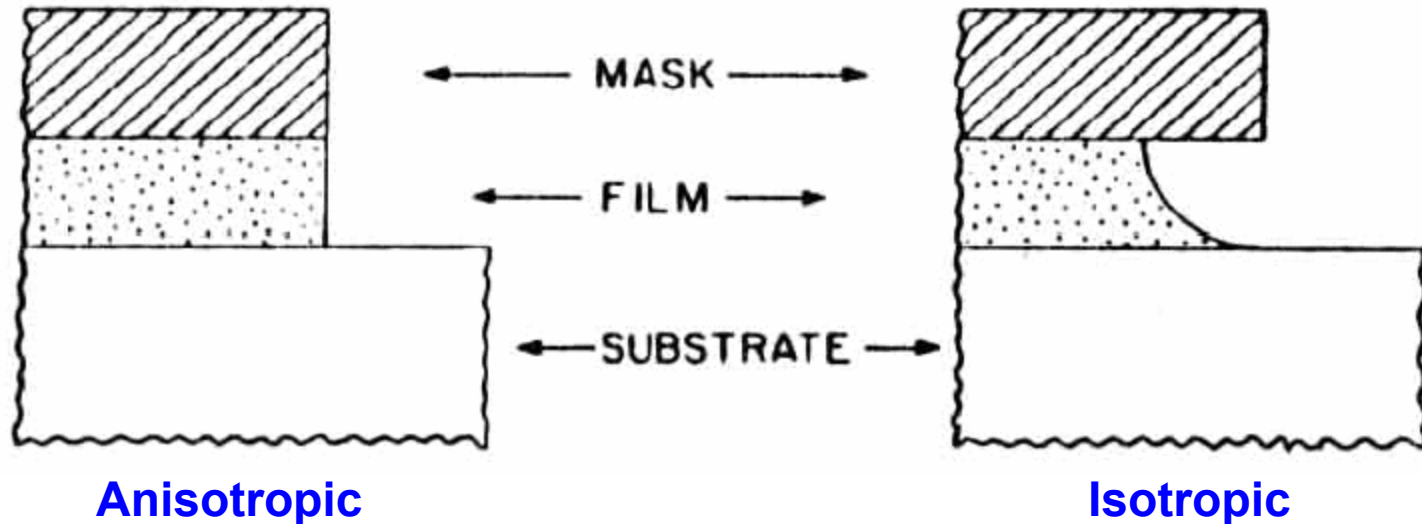
- Etch Selectivity:

- relative (ratio) of the etch rate of the thin film to the mask, substrate, or another film

- Etch Geometry:

- sidewall slope (degree of anisotropy)

# Types of Etching Processes



- **Anisotropic:**

- best for making small gaps and vertical sidewalls
- typically more costly

- **Isotropic :**

- quick, easy, cheap
- best to use with large geometries, when sidewall slope does not matter, undercut/release
- rounding of sharp anisotropic corners to avoid stress concentration

# Wet Etching

- Mixtures of acids, bases, and water
  - HF, H<sub>3</sub>PO<sub>4</sub>, H<sub>2</sub>SO<sub>4</sub>, KOH, H<sub>2</sub>O<sub>2</sub>, HCl, ..
- Can be used to etch many materials
  - Si, SiO<sub>2</sub>, Si<sub>3</sub>N<sub>4</sub>, PR, Al, Au, Cu,...
- Etch Rate:
  - wide range
- Etch Selectivity
  - typically quite high
  - sensitive to contamination
- Etch Geometry:
  - typically isotropic, some special cases are anisotropic

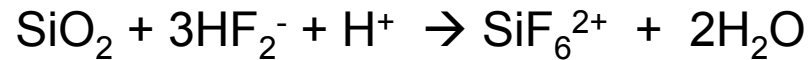
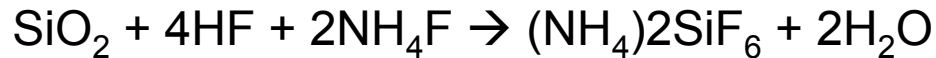
# Hydrofluoric Acid (for SiO<sub>2</sub>)

- Selective (room temperature)
  - etches SiO<sub>2</sub> and not Si
  - will also attack Al, Si<sub>3</sub>N<sub>4</sub>,...
- Rate depends strongly on concentration
  - maximum: 49% HF (“concentrated”) ~ >2 μm/min
  - controlled: 5 to 50:1 (“timed”) ~ <0.1 μm/min
- Dangerous !
  - not a strong acid
  - deceptive (looks just like water)
  - penetrate skin (adsorption) and attacks slowly
  - will target bones
- Etch Geometry
  - completely isotropic (used to undercut/release)
- Reactions:  
$$\text{SiO}_2 + 6\text{HF} \rightarrow \text{H}_2\text{SiF}_6(\text{aq}) + 2\text{H}_2\text{O}$$

# Buffered HF (for SiO<sub>2</sub>)

Buffered HF (BHF), also called Buffered oxide etch (BOE)  
addition of NH<sub>4</sub>F to HF solution

- control the pH value
- replenish the depletion of the fluoride ions to maintain stable etching performance



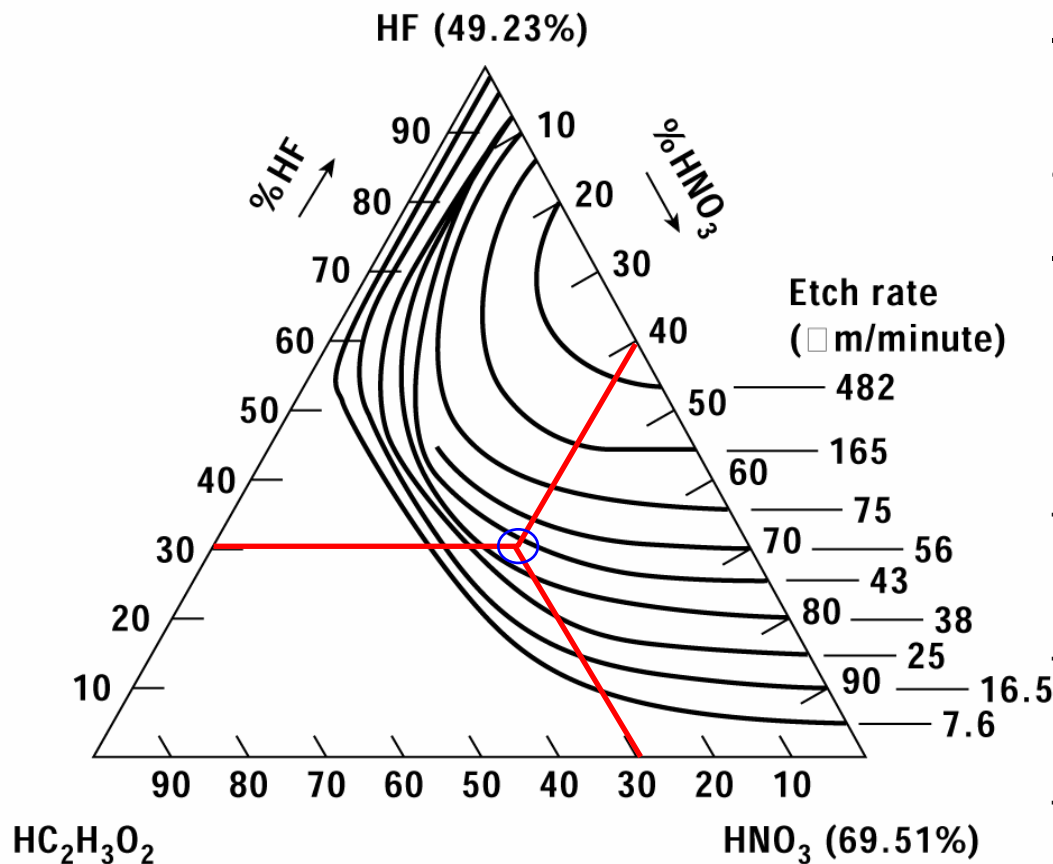
# Phosphoric Acid (for $\text{Si}_x\text{N}_y$ )

- Selectively (high-temperature)
  - etches  $\text{Si}_x\text{N}_y$  and not Si or  $\text{SiO}_2$
  - etches Al and other metals much faster
- Rate:
  - Slow !  $R \sim >0.0050 \mu\text{m}/\text{min}$  for  $\text{H}_3\text{PO}_4$  at  $160^\circ\text{C}$
- Tough Masking Materials Needed
  - PR will not survive
  - Oxide is typically used

## Etch Geometry

- completely isotropic

# HNA (for Silicon)



**Iso-etch Curve** (From Robbins. et al)

-mixture of nitric (HNO<sub>3</sub>), hydrofluoric (HF) and acetic (CH<sub>3</sub>COOH) acids

-HNO<sub>3</sub> oxides Si, HF removes SiO<sub>2</sub>, repeat...



-high HNO<sub>3</sub>:HF ratio (etch limited by oxide removal)

-low HNO<sub>3</sub>:HF ratio (etch limited by oxide formation)

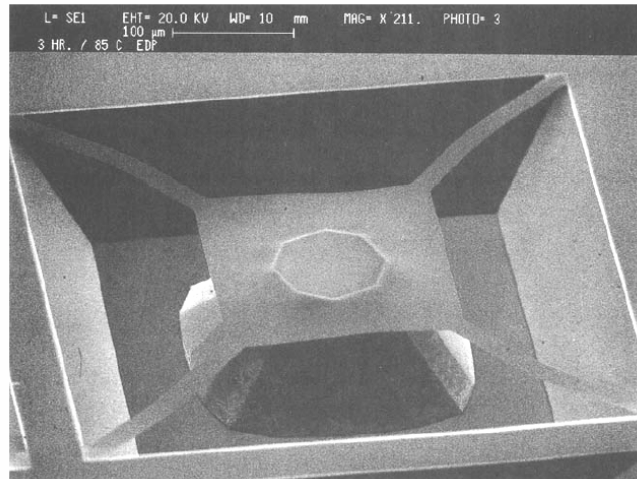
-dilute with water or acetic acid (CH<sub>3</sub>COOH)

-acetic acid is preferred because it prevents HNO<sub>3</sub> dissociation

# Orientation-Dependent Etching

## •KOH

- $\text{Si} + \text{OH}^- + 2\text{H}_2\text{O} \rightarrow \text{SiO}_2(\text{OH})_2^{2-} + 2\text{H}_2(\text{g})$
- Etch rate :  $\{110\} > \{100\} \gg \{111\}$
- Used at the elevated temperature ( $\sim 80^\circ\text{C}$ )
- Resist will not survive, oxide is attacked slowly
- Nitride is not attacked (best masking material)

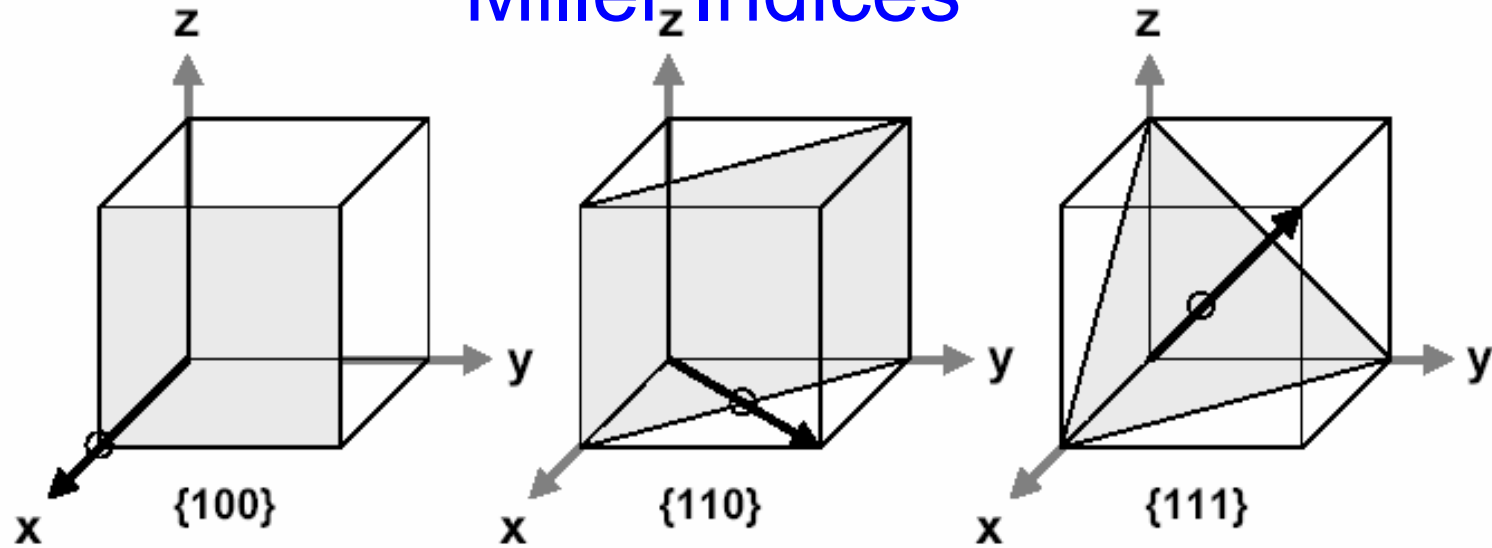


Neuron well



Optical DNA Sensor

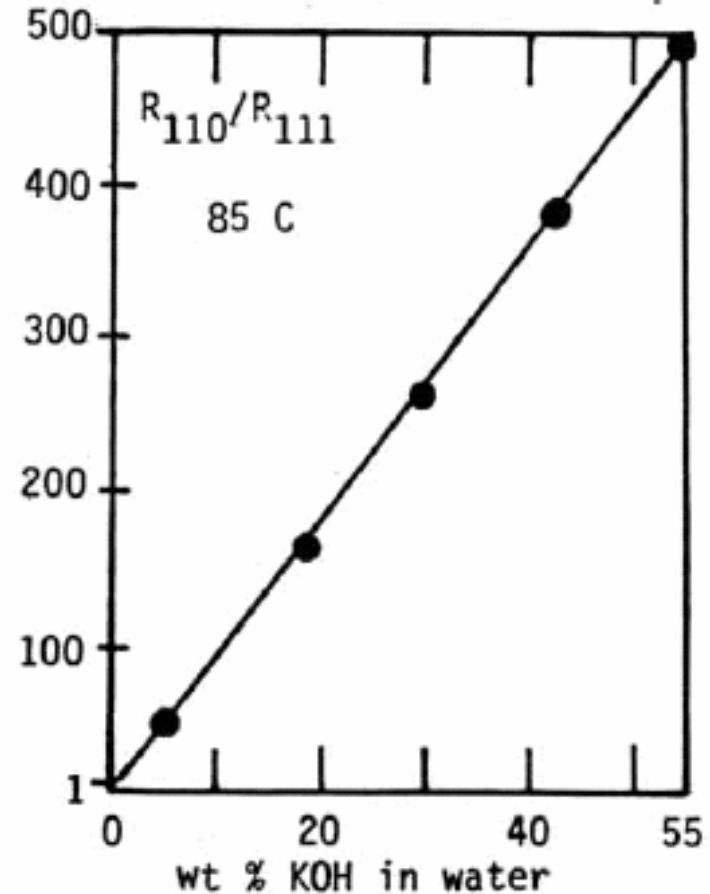
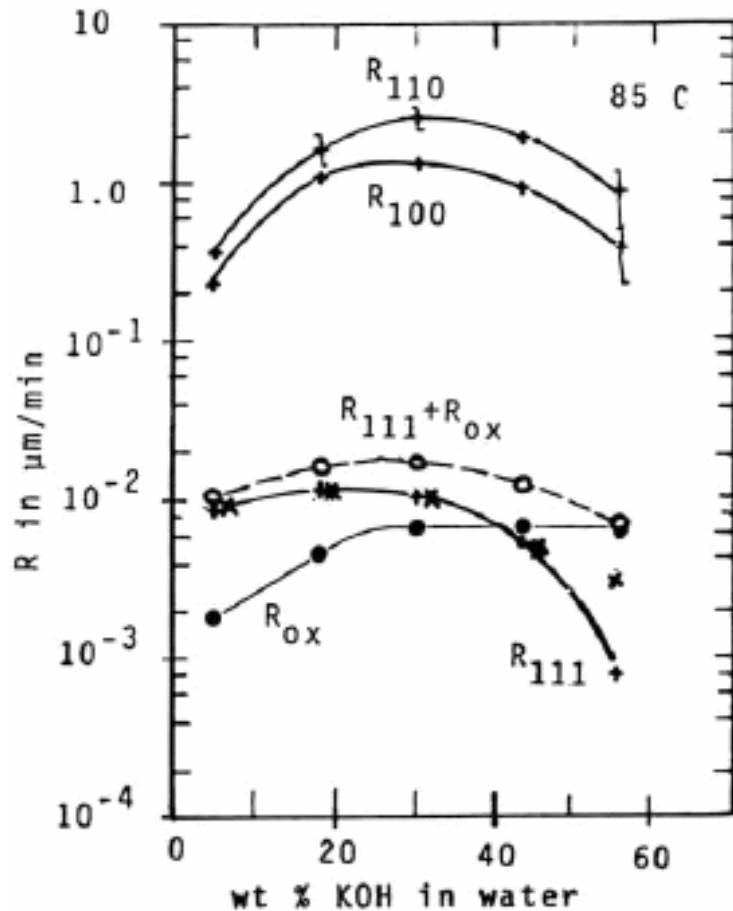
# Miller Indices



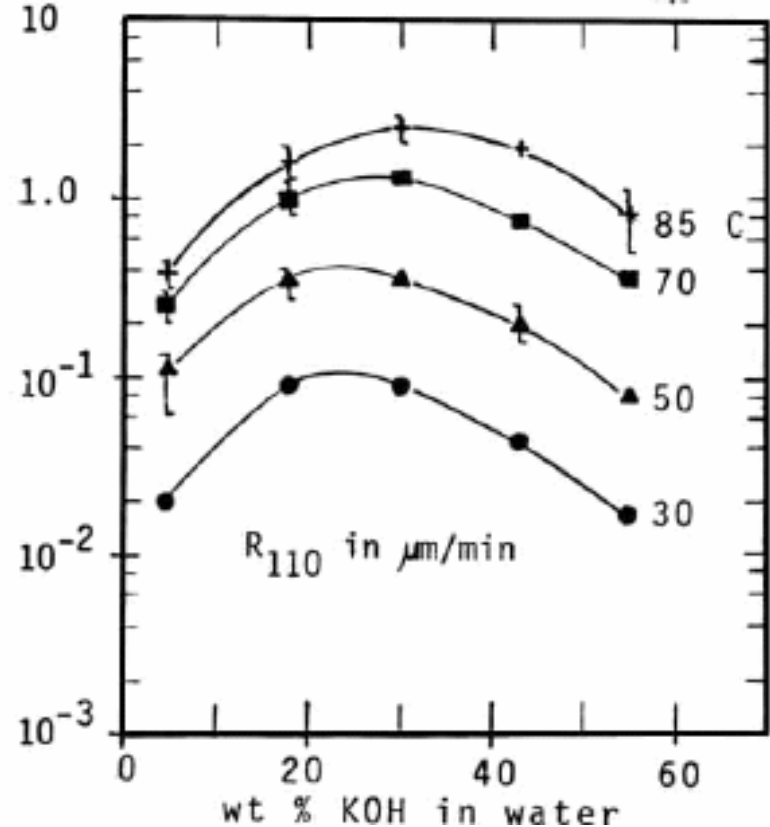
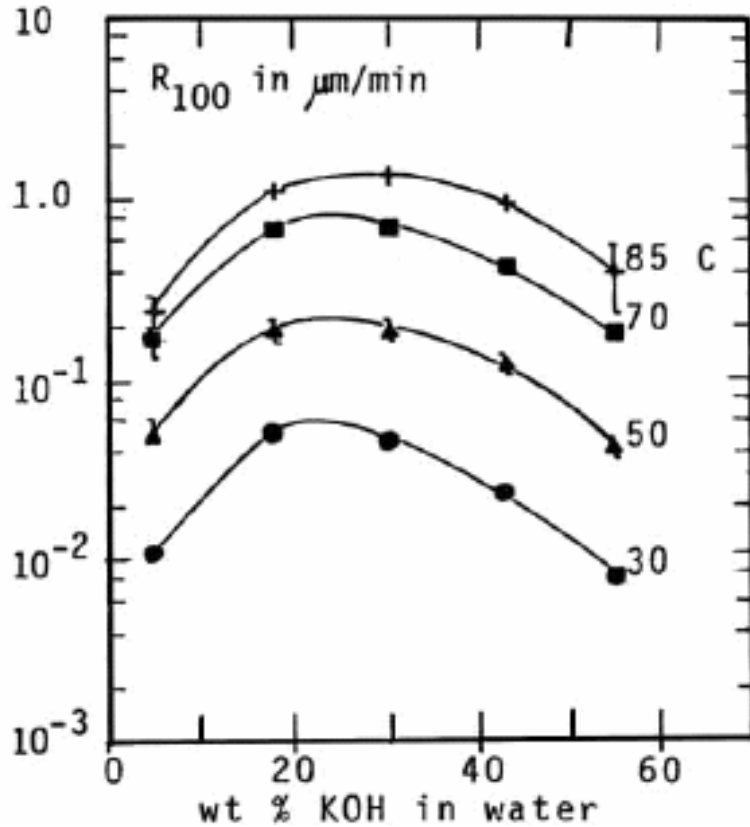
Miller Indices of a plane is determined by

- Take the intercepts of the plane along the crystallographic axes  
eg. 2, 1, 3
- The reciprocal of the three integers are taken and are multiplied by the smallest common denominator  
eg.  $1/2, 1/1, 1/3$  (multiple by 6)  $\rightarrow (3, 6, 2)$
- If a plane is parallel to an axis, its intercept is at infinity and its Miller index is zero
- Important plans in Si lattice
  - **{1,0,0}** : (1,0,0), (01,0), (0, 0,1), (1,0,0), (0,1, 0),...
  - **{1,1,0}**
  - **{1,1,1}**

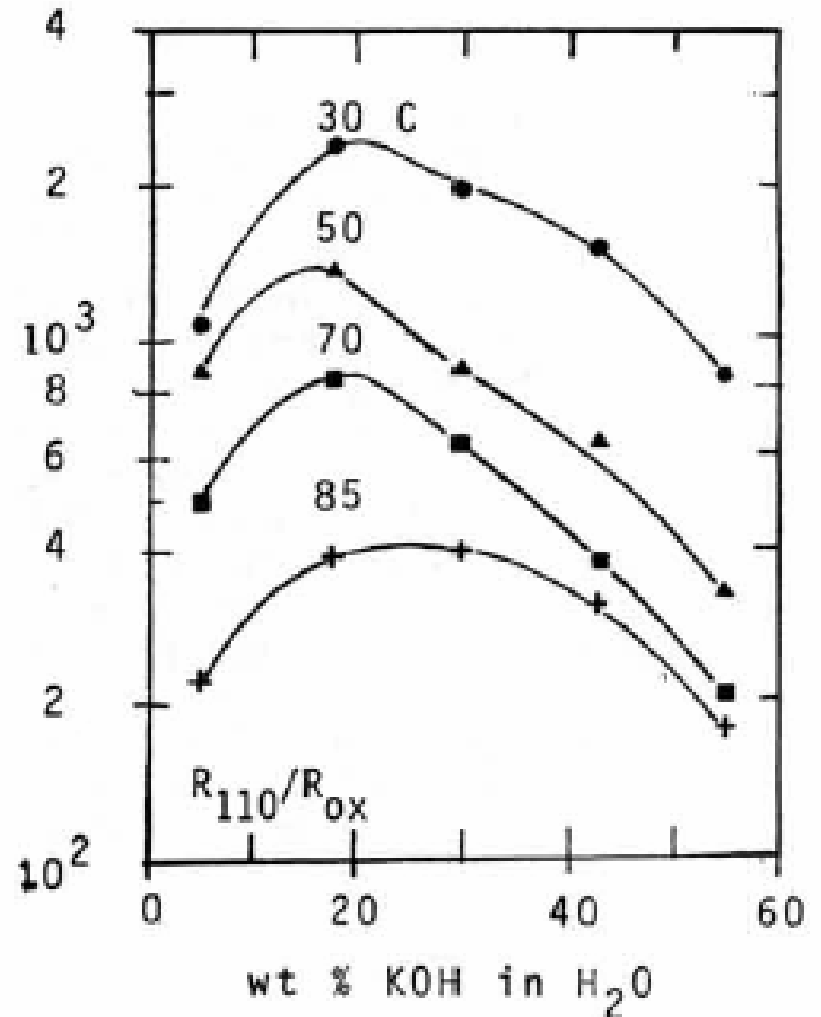
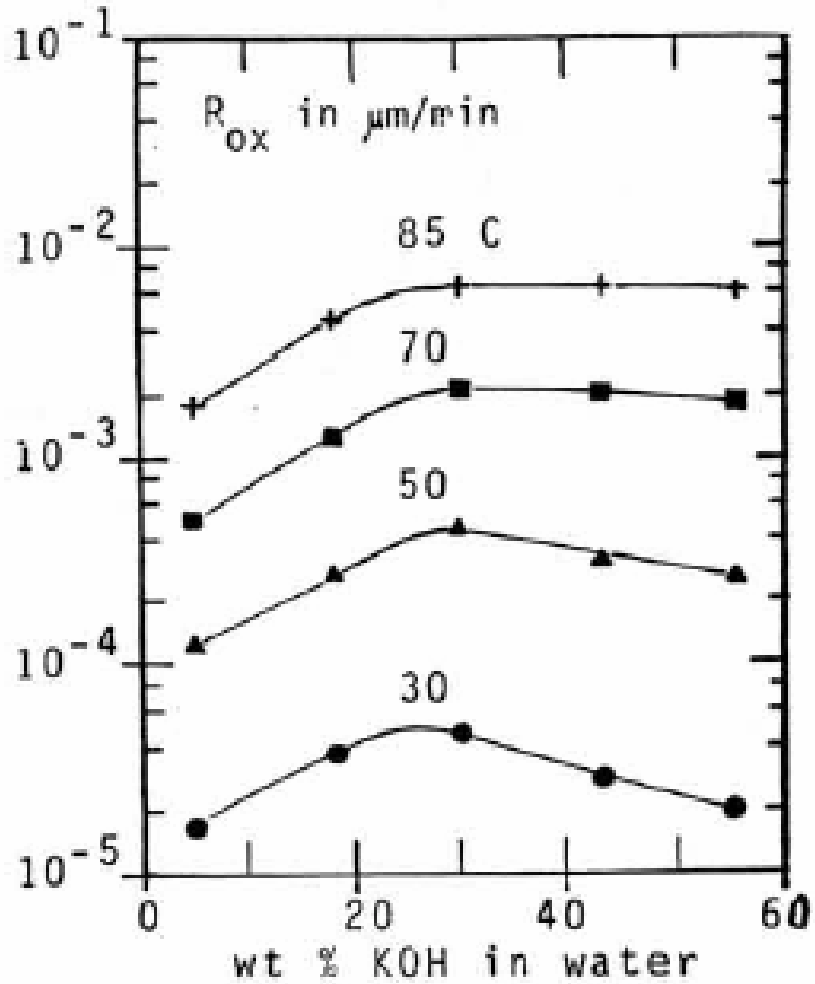
# Etch rate of Si in KOH Depends on Crystallographic Plane



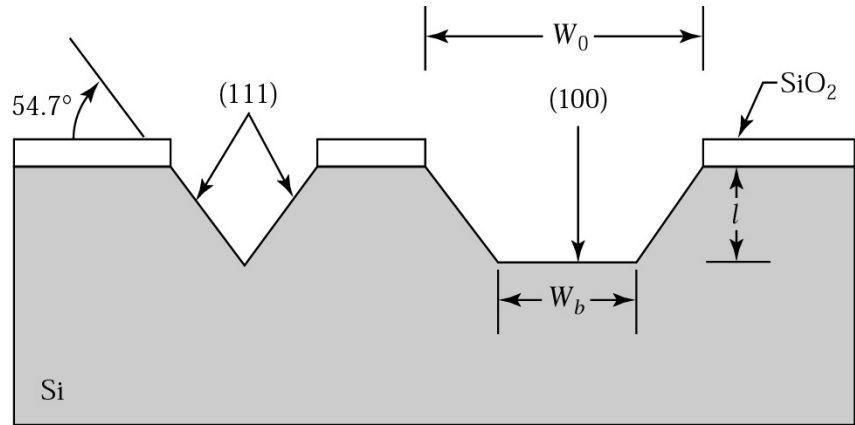
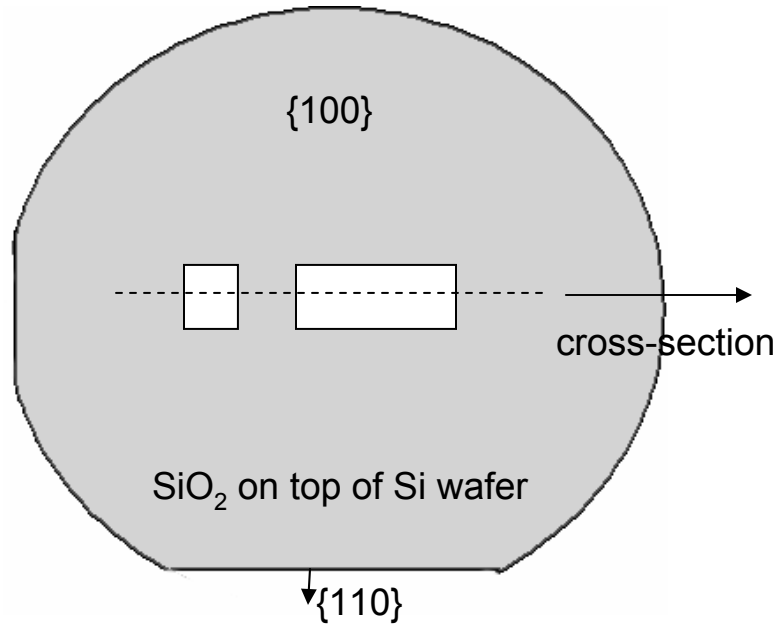
# Etch rate of Si in KOH Depends on Temperature



# Etch Rate of Oxide in KOH



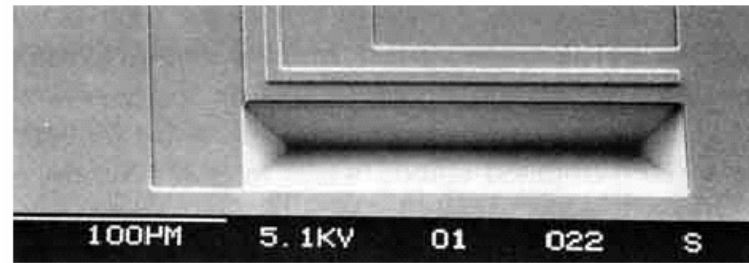
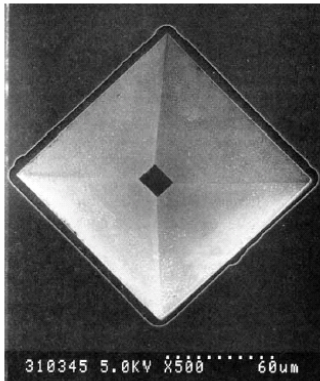
# Anisotropic Etching : Si in KOH



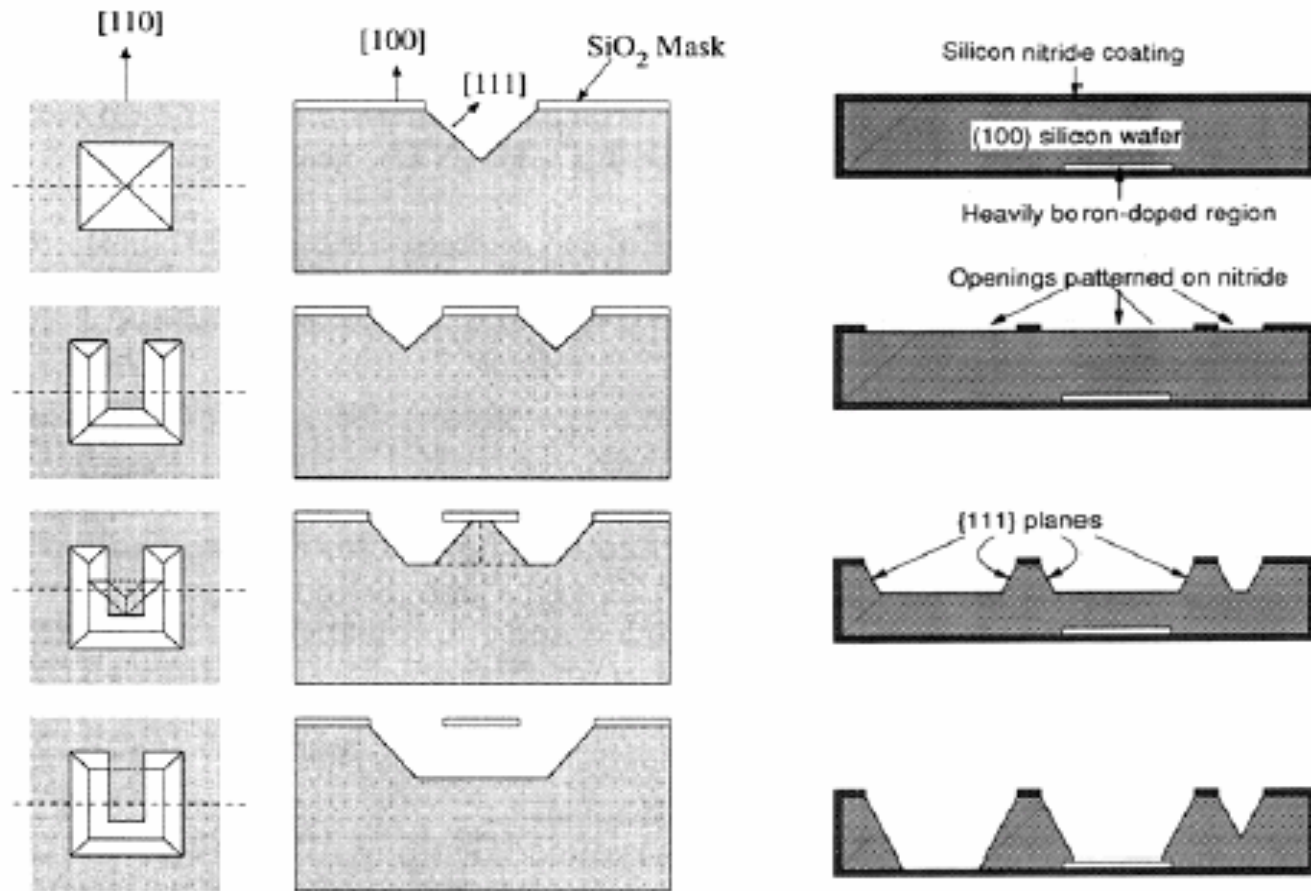
(a)

$$W_b = W_0 - 2 \cdot l \cdot \cot 54.7^\circ$$

$$W_b = W_0 - \sqrt{2} \cdot l$$



# Bulk Micromachining



# Bulk Micromachining

